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WELLS ST. JOHN, P.S.

5098383424 P. 07/13  
Sheet 1 of 1

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1427		SERIAL NO. 09322,903		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Zhiping Yio et al.				
				FILING DATE April 26, 2000		GROUP 2815		
U.S. PATENT DOCUMENTS								
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
YX	AA	6,133,618	10-2000	Steiner				
	AB	5,994,217	11-1999	Ng				
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	AK							
	AL							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
YX	AR		Wong, S. "Silicon Processing for the VLSI Era," Vol. 1, pgs. 417-418.					
YX	AS		Wolf, S. "Silicon Processing for the VLSI Era," Vol. 2, pgs. 48-49 and 435.					
EXAMINER				DATE CONSIDERED				
YX/MS				2/17/04				
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				GROUP 2815				
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
JK	AA	US 2001/0003064 A1	06-2001	Ohno			Dec. 4, 2000	
M	AB	US 2003/0015511 A1	01-2003	Chang et al.			Jul. 3, 2001	
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FOREIGN PATENT DOCUMENTS								
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EXAMINER				DATE CONSIDERED				
JKS/ha				2/17/04				
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